

Notice of References Cited

Application/Control No.

09/265,119

Applicant(s)/Patent Under
Reexamination
PERI ET AL.

Examiner

Ayal I. Sharon

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,991,199	11-1999	Brigati et al.	365/185.11
	B	US-6,011,717	01-2000	Brigati et al.	365/185.05
	C	US-6,141,254	10-2000	Devin et al.	365/185.12
	D	US-6,275,960	08-2001	Cappelletti et al.	714/718
	E	US-5,937,423	08-1999	Robinson, Kurt B.	365/52
	F	US-5,603,001	02-1997	Sukegawa et al.	711/103
	G	US-5,508,971	04-1996	Cernea et al.	365/185.14
	H	US-5,663,901	09-1997	Wallace et al.	365/185.11
	I	US-5,596,532	01-1997	Cernea et al.	365/185.18
	J	US-5,872,994	02-1999	Akiyama et al.	365/185.33
	K	US-6,092,160	07-2000	Marsters, Jonathan Iain	365/185.11
	L	US-5,912,848	06-1999	Bothwell, Leslie Innes	365/185.29
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Andretta, F., Peri, M., Pozzi, C. "Testing of the ST9 Microcontroller". Proceedings of the 20th EUROMICRO Conference, 1994. Sept. 5-8, 1994. pp.322-328.				
	V	"Onwards and Upwards: New developments in 8-bit Micros". Challenge: News and Views from STMicroelectronics, March 1999.				
	W	Brown et al. "Simultaneous Code Execution and Data Storage in a Single Flash Memory Chip for Real Time Wireless Communication Systems". Proceedings of the 40th Midwest Symposium on Circuits and Systems, 1997. Aug. 3-6, 1997. pp. 740-745, vol. 2.				
	X	Nakamura et al. "An Intelligent Subprocessor for Hardware Emulation with 20-MOPS performance." IEEE Journal of Solid-State Circuits. Nov. 1991. Vol. 26, Issue 11. pp.1662-1668.				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.